AMETEK SI

SolarLab XM

Photoelectrochemical test system

Measurement system for solar-cell and photoelectrochemical characterization, including perovskite and dye-sensitized cells.



System modules	Wavelength range	Intensity range
Potentiostat, FRA and PhotoEchem module [1]	**350–1100 nm** [1]	**6 decades with ND filter** [1]

Specifications

MEASURING RANGE

Intensity range	6 decades with ND filter	[1]

POWER & BATTERY

Typical LED stability at maximum power	<2% drift after 24 hours	[1]

MECHANICAL

Wavelength range	350–1100 nm	[1]
Maximum beam diameter / cell size	1 cm	[1]

ORDERING & ACCESSORIES

IPCE option	IPCE for quantum efficiency (option)	[1]

GENERAL

System modules	Potentiostat, FRA and PhotoEchem module	[1]
Maximum beam divergence	4°	[1]
Light-source calibration	NIST-traceable	[1]
Measurement modes	IMPS, IMVS, impedance, I–V, photovoltage decay, charge extraction	[1]

Sources

[1] **SolarLab XM Photoelectrochemical Test System**
AMETEK Scientific Instruments · product-page · product page · checked 2026-10-16
https://www.ameteksi.com/products/solar-test-systems/solarlab-xm-photoelectrochemical

Every value is taken from the manufacturer's own document; the number after the value refers to the source list. Always check against the latest datasheet before ordering.

The data comes from the manufacturer's published documents. Manufacturers may change specifications; the current configuration and performance are confirmed in the quotation.